



Sheet 1 of 1

Substitute Form PTO-1449 (Modified)	U.S. Department of Commerce Patent and Trademark Office	Attorney's Docket No. 08935-251002	Application No. 10/796,739
Information Disclosure Statement by Applicant (Use several sheets if necessary) (37 CFR §1.98(b))		Applicant William L. Bowden et al.	
		Filing Date March 9, 2004	Group Art Unit 1745

U.S. Patent Documents							
Examiner Initial	Desig. ID	Document Number	Publication Date	Patentee	Class	Subclass	Filing Date If Appropriate
	AA						
	AB						
	AC						
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Foreign Patent Documents or Published Foreign Patent Applications							
Examiner Initial	Desig. ID	Document Number	Publication Date	Country or Patent Office	Class	Subclass	Translation
							Yes No
LJW	AF	11-329424	11/30/99	Japan (Abstract)			Abst X
	AG	11-329424	11/30/99	Japan			X
LJW	AH	0 728 701 A1	08/28/96	EPO			
LJW	AI	0 279 235 A1	08/24/88	EPO			
	AJ						
	AK						

Other Documents (include Author, Title, Date, and Place of Publication)		
Examiner Initial	Desig. ID	Document
LJW	AL	International Search Report, PCT/US02/36937, mailed 29/04/2005
	AM	
	AN	
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AL	11-329424	11/30/99	Japan (English Abstract Only)				X
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